

Search Notes

Application/Control No.

10/587,576

Examiner

Hai H. Huynh

Applicant(s)/Patent under
Reexamination

NAKAYAMA ET AL.

Art Unit

3747

SEARCHED

Class	Subclass	Date	Examiner
123	435-436	11/7/2007	HHH
701	110-111	11/7/2007	HHH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
above	search	11/7/2007	HHH

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	11/7/2007	HHH